



10/8/10

**RELIABILITY MONITOR REPORT
FOR**

MFN Dual Poly 0.8 μ m BiCMOS (MB10)

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX2116UTL+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 7751 QUANTITY: 80 FAILS: 0 FITS 14.7

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2009 and 9/30/2010 .

Process Information:

Process Description: MFN Dual Poly 0.8µm BiCMOS (MB10)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1027	MAX2116UTL+	135C	500 HRS	80	0	ND71L21D0B
Total:						0	
FAILURE RATE:	MTTF (YRS): 7751		QUANTITY: 80	FAILS: 0	FITS: 14.7		